

Original text of DCR

Affected documents:

ESCC 3009 Issue 2 (and ESCC 3001) - 3009/008 Issue 4 (and other 3009/xxx detail specifications)

Page:

3009 pages 21 and 28 - 3009/008 pages 10 and 11

Paragraph:

3009 para 8.10 and 12.4 - 3009/008 para 2.3.2 and

Original text:

3009 para 8.10 CAPACITANCE-TEMPERATURE CHARACTERISTICS

The capacitance-temperature characteristics of the components mounted in accordance with Para. 8.6 shall be measured as specified in Intermediate and End-Point Electrical Measurements in the Detail Specification. The following details shall apply:

- Test Conditions:

(a) For type I capacitors: Temperature Coefficient in accordance with Para. 8.3.1.5.

(b) For type II capacitors: Temperature Characteristic in accordance with Para. 8.3.1.6.

Modified text:

3009, 8.10 TEMPERATURE CHARACTERISATION

The temperature characteristics of the components shall be measured as specified in Intermediate and End-Point Electrical Measurements in the Detail Specification. The following details shall apply:

(a) Insulation Resistance in accordance with Para 8.3.1.3 at maximum operating temperature rating $\pm 2^{\circ}\text{C}$ as specified in the Detail Specification.

(b) For type I capacitors: Temperature Coefficient in accordance with Para. 8.3.1.5.

(c) For type II capacitors: Temperature Characteristic in accordance with Para. 8.3.1.6.

3009, 12.4 Chart F4 - rename box CAPACITANCE-TEMPERATURE CHARACTERISTICS to CAPACITANCE-TEMPERATURE CHARACTERISTICS and change note 7 accordingly.

3009/008, 2.3.2 and 2.4 see appended implementation of changes.

Justification:

Elimination of levels B and C resulted in an unwanted removal of High Temperature Insulation Resistance definition. In order to re-introduce the parameter, capacitance-temperature characteristics is changes to temperature characterisation and Insulation Resistance added to High and Low Temperature Measurement Table in the detail specifications.

In order to avoid changes (and cost addition) to previous situation, the performance of the measurement is limited to Chart F4 Qualification and Periodic Testing through the addition of a note to the High and Low Temperature Measurement Table. For procurement, this parameter is therefore guaranteed and not tested in a similar way as other parameters in ICs specifications for example.